PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of

ANDREJ S MITROVIC

Group Art Unit:

Application No.:

Examiner:

Filed: November 25, 2003

Confirmation No.:

For: PLASMA PROCESSING SYSTEM AND METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. As this application is being filed after June 30, 2003, no copies of the cited U.S. patents are enclosed; however, a copy of each non-patent literature reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed with the Non-Provisional application. No certification or fee is required.

Dale S. Lazar

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Respectfully Submitted.

Date: November 25 2003

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PTO/SB/08a (05-03)

Approved for use through 04/30/2003, OMB 0651-0031 U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Substitut	e for form 1449A/PTO		Complete if Known		
			Application Number		
INF	ORMATION DIS	CLOSURE	Filing Date	11/25/2003	
	TEMENT BY A		First Named Inventor	ANDREJ S MITROVIC	
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Sheet	1	of 1	Attorney Docket Number	071469-0306508	

				U.S. PATENT	DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (it k}		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1	^{US-} 6,613,588	B2	09-02-2003	NAKANO et al.	
	2	^{US-} 5,294,806		03-15-1994	BATCHELDER et al.	
	3	^{US-} 5,192,870		03-9-1993	BATCHELDER et al.	
	4	^{US-} 5,622,595		04-22-1997	GUPTA et al.	
	5	US- 5,328,555		07-12-1994	GUPTA	
	6	us- 6,576,559	B2	06-10-2003	NAKATA et al.	
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FOREIGN PATENT DOCUMENTS									
Examiner Initials*	Cite No.¹	Foreign Patent Document Country Code ³⁻ Number ⁴⁻ Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	т6			
						1.			

Examiner	Date	
Signature	Considered	

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This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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				Application Number			
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STATE	MENT BY	APPLIC	CANT	First Named Inventor	ANDREJ S MITROVIC		
				Art Unit			
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Sheet	1	of	1	Attorney Docket Number	071469-0306508		

	NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*	Cite No. Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publis and/or country where published.							
	Α	WOLBERG, "Spatial Transformations," Digital Image Warping, IEEE Computer Society Press (Los Almaitos, CA 90720), p. 41-94, (1990).						
	В	SELWYN ET AL., "Rastered laser light scattering studies during plasma processing: Particle contamination trapping phenomena," J.Vac.Sci. Technol., American Vacuum Society, Vol. A9 (No. 5), p. 2817-2824, (September/October 1991).						
	С	SELWYN ET AL., "Trapping and behavior of particulates in a radio frequency magnetron plasma etching tool," J.Vac.Sci. Technol., American Vacuum Society, Vol. A 1 (No. 4), p. 1132-1135, (July/August 1993).						
	D	SELWYN, "5.4 Particulate Detection by Laser Light Scattering," Optical Diagnostic Techniques for Plasma Processing, M-11, American Vacuum Society, p. 135-138, 151-152, (1993).						
	Е	CARLILE ET AL., "Electrostatic trapping of contamination particles in a process plasma environment," Applied Physics Letter, American Institute of Physics, Vol. 59 (No. 10), p. 1167-1169, (September 2, 1991).						
	F	SELWYN ET AL., "Particle trapping phenomena in radio frequency plasmas," Apply. Phys. Lett., American Institute orf Physics, Vol. 57 (No. 18), p. 1876-1878, (October 29, 1990).						

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